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PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Masao MATSUDA

Serial No. 09/980,097

GROUP 2131

Filed November 29, 2001

Examiner Unassigned

INTELLECTUAL PROPERTY RIGHT MANAGEMENT SYSTEM

INFORMATION DISCLOSURE STATEMENT

RECEIVED

Commissioner for Patents

MAR 04 2002

Washington, D.C. 20231

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Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed sheet.

A concise explanation of the relevance of these items is that these references were cited in the International Patent Office in the corresponding International application Serial No. PCT/JP01/02594, filed March 28, 2001. A copy of the International Search Report in which they were cited is attached hereto.

Respectfully submitted,

YOUNG & THOMPSON

By

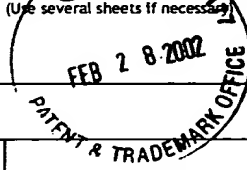
Robert J. Patch
Attorney for Applicant
Registration No. 17,355
745 South 23rd Street
Arlington, VA 22202
Telephone: 703/521-2297

February 28, 2002

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
PF-2850/USSERIAL NO.
09/980,097**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use several sheets if necessary)

37 CFR 1.98(b)

APPLICANT
Masao MATSUDAFILING DATE
November 29, 2001GROUP
2131**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
	AI	A 9-69112	03/97	JP			with English abstract
	AJ	A 11-175570	07/99	JP			with English abstract
	AK						
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						

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OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

	AT	Masao TAKAHASHI et al., "Mitsubishi Integrated Patent System (MIPAT)," V. 39, 1998, pp. 252-257. (with English abridged translation)
	AU	
	AV	
	AX	
	AY	

EXAMINER**DATE CONSIDERED**

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.